

Product Data Sheet

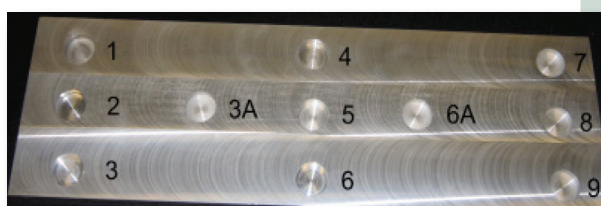
# Cu/In/Ga Target (380mm x 126mm x 6mm)

## Test Scope

For 11 areas of the target (as identified in the pictures on the right), 3 samples were extracted and analyzed. The three samples were from the top (1-2mm depth), middle (3-4mm depth), and bottom (5-6mm depth). Tests were performed on ICP-OES which has a standard variation of 0.12%.

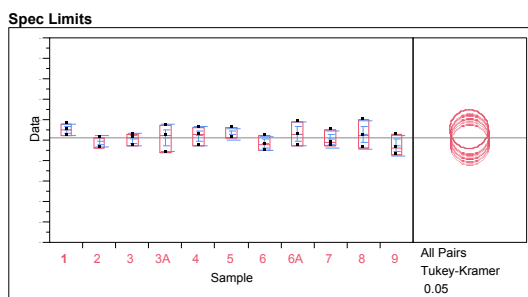


Test Target



Test Target

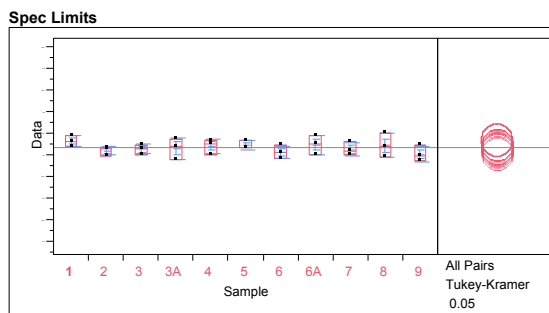
### Oneway (JMP) Analysis of Data By Sample Attribute=Cu



#### Std Deviations

Level	Number	Std Dev
1	3	0.030000
2	3	0.028868
3	3	0.030551
3A	3	0.065574
4	3	0.045826
5	3	0.028868
6	3	0.035119
6A	3	0.060000
7	3	0.041633
8	3	0.070238
9	3	0.051316

### Oneway (JMP) Analysis of Data By Sample Attribute=CuIn



#### Std Deviations

Level	Number	Std Dev
1	3	0.001212
2	3	0.000994
3	3	0.001128
3A	3	0.002505
4	3	0.001700
5	3	0.001068
6	3	0.001448
6A	3	0.002283
7	3	0.001550
8	3	0.002757
9	3	0.001833

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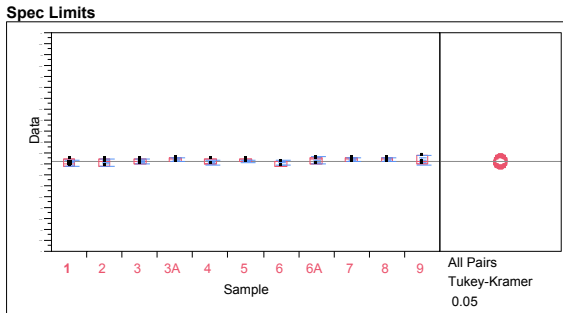
ASIA: Singapore, Cheongju: +65 6268 8678  
 CHINA: Suzhou, Shenzhen, Liuzhou: +86 (0)512 628 34900  
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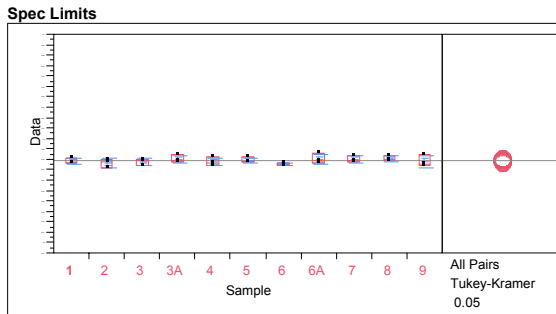
## Cu/In/Ga Target (380mm x 126mm x 6mm)

### Oneway (JMP) Analysis of Data By Sample Attribute=GA



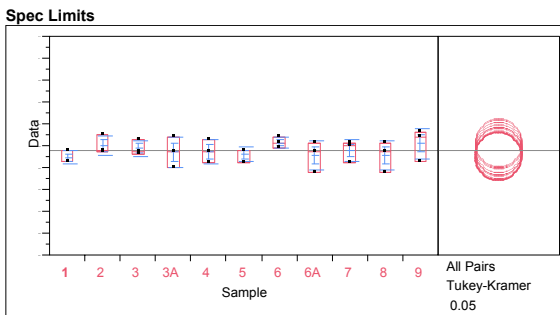
Std Deviations		
Level	Number	Std Dev
1	3	0.015275
2	3	0.015275
3	3	0.010000
3A	3	0.010000
4	3	0.011547
5	3	0.005774
6	3	0.011547
6A	3	0.015275
7	3	0.010000
8	3	0.010000
9	3	0.020817

### Oneway (JMP) Analysis of Data By Sample Attribute=GallI



Std Deviations		
Level	Number	Std Dev
1	3	0.000298
2	3	0.000426
3	3	0.000302
3A	3	0.000393
4	3	0.000397
5	3	0.000236
6	3	0.000125
6A	3	0.000456
7	3	0.000348
8	3	0.000271
9	3	0.000616

### Oneway (JMP) Analysis of Data By Sample Attribute=In



Std Deviations		
Level	Number	Std Dev
1	3	0.028868
2	3	0.043589
3	3	0.037859
3A	3	0.070000
4	3	0.055076
5	3	0.034641
6	3	0.025166
6A	3	0.066583
7	3	0.049329
8	3	0.066583
9	3	0.070000

## Summary

The statistical equivalence of all the preceding test data (for Cu/In Ratio, Ga/In Ratio, Cu wt %, In wt %, Ga wt %) suggest that the material uniformity of the target is very high. The major contributor to the minimal variation shown within the test data is the inherent variation induced by the test equipment.

This product data sheet is provided for general information only. It is not intended, and shall not be construed, to warrant or guarantee the performance of the

products described which are sold subject exclusively to written warranties and limitations thereon included in product packaging and invoices.

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[askus@indium.com](mailto:askus@indium.com)

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